



Application/Control No.	Applicant(s)/Pate Reexamination YUMIBA ET AL.			
Examiner	Art Unit			
Shin-Hon Chen	2131	Page 1 of 1		

## **U.S. PATENT DOCUMENTS**

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	В	US-6,694,023	02-2004	Kim, Byung-Jun	380/203
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## **NON-PATENT DOCUMENTS**

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Γ	*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)			
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